

Product Name: Smart Phone	Report No: ITEZA202300083RF7
Product Model: S punk, S punk Pro, S punk S, S punk E, S punk SE, S punk Plus, S punk Max, S punk Ultra, S cyber, S cyber Pro, S cyber S, S cyber E, S cyber SE, S cyber Plus, S cyber Max, S cyber Ultra	Security Classification: Open
Version: V1.0	Total Page: 53

# **TIRT Testing Report**

Prepared By:	Checked By:	Approved By:	chnology Sea
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som long	Stone Tang	Long Wany	Shenzhen S



# RF TEST REPORT

FCC ID: 2AX4YSPUNK

According to

FCC CFR Title 47 Part 2
FCC CFR Title 47 Part 22 Subpart H
FCC CFR Title 47 Part 24 Subpart E
FCC CFR Title 47 Part 27 Subpart C
FCC CFR Title 47 Part 90 Subpart S
ANSI C63.26:2015

KDB 971168 D01 Power Meas License Digital Systems v03r01

Applicant:	Shenzhen DOOGEE Hengtong Technology CO.,LTD	
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No.	
Address.	22, Longhua New District, Shenzhen, China	
Manufacturer:	Shenzhen DOOGEE Hengtong Technology CO.,LTD	
Address:	B, 2/F, Building A4, Silicon Valley Power Digital Industrial Park, No.	
Address.	22, Longhua New District, Shenzhen, China	
Sample No:	1000031136	
Product Name:	Smart Phone	
Brand Name:	DOOGEE	
	S punk, S punk Pro, S punk S, S punk E, S punk SE,	
Model No.:	S punk Plus, S punk Max, S punk Ultra, S cyber,	
Woder No	S cyber Pro, S cyber S, S cyber E, S cyber SE,	
	S cyber Plus, S cyber Max, S cyber Ultra	
Test No.:	S punk	

Date of Receipt:	2024/04/09
Date of Test:	2024/04/09~2024/04/22
Issued Date:	2024/04/30
Testing Lab:	TIRT

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**4.12 TEST SETUP PHOTO** 



# **History of this test report**Original Report Issue Date: 2024.04.30

- No additional attachment
- o Additional attachments were issued following record

Attachment No.	Issue Date	Description



# TEST SUMMARY

Test Item	Section in CFR 47	Result
	Part 1.1307	Pass*(Please refer to
RF Exposure (SAR)	Part 2.1093	SAR Report)
	Part 2.1046	
	Part 22.913(a)	
	Part 24.232(b)	
DE Outsut Davis	Part 27.50(b)	Dana
RF Output Power	Part 27.50(c)	Pass
	Part 27.50(d)	
	Part 27.50(h)	
	Part 90.635	
	Part 2.1046	
Pook To Average Patie	Part 22.913(d)	Pass
Peak-To-Average Ratio	Part 24.232 (d)	Fd55
	Part 27.50(d)	
Modulation Characteristics	Part 2.1047	N/A
	Part 2.1049	
000/ 8 26 dB Occupied Bandwidth	Part 22.917	Pass
99% & -26 dB Occupied Bandwidth	Part 24.238	Pass
	Part 27.53(a)	
	Part 2.1051	
	Part 22.917	
	Part 24.238	
Spurious Emissions at Antenna Terminal	Part 27.53(c)(f)	Pass
opunous Emissions at Antenna Terminal	Part 27.53(g)	1 433
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1053	
	Part 22.917	
	Part 24.238	
Field Strength of Spurious Radiation	Part 27.53(c)(f)	Pass
Substitution of a spanious readiation	Part 27.53(g)	1 400
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	



	_	
	Part 2.1051	
	Part 22.917	
	Part 24.238	
Out of hand emission Band Educ	Part 27.53(c)(f)	Dana
Out of band emission, Band Edge	Part 27.53(g)	Pass
	Part 27.53(h)	
	Part 27.53(m)	
	Part 90.691	
	Part 2.1055(a)(1)(b)	
	Part 22.355	
Frequency stability vs. temperature	Part 24.235	Pass
	Part 27.54	
	Part 90.213	
	Part 2.1055(d)(1)(2)	
Frequency stability vs. voltage	Part 22.355	
	Part 24.235	Pass
	Part 27.54	
	Part 90.213	

Note: 1. Pass: The EUT complies with the essential requirements in the standard.

<sup>2.</sup> The conclusion of this test report is judged by actual test data without considering measurement uncertainty.



# 2 GENERAL INFORMATION

### 2.1 GENERAL DESCRIPTION OF EUT

Description of Device (EUT)

EUT Name : Smart Phone

Model No. : S punk, S punk Pro, S punk S, S punk E, S punk SE, S punk Plus,

S punk Max, S punk Ultra, S cyber, S cyber Pro, S cyber S, S cyber E,

S cyber SE, S cyber Plus, S cyber Max, S cyber Ultra

DIFF. : There is no difference except the name of the model. All tests are made with

the S punk model.

Power supply : DC 3.87V from battery or DC11V from adapter

Support Bands : LTE Band 2/4/5/7/25/26/38//41/66

Channel Bandwidth : LTE Band 2: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 4: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 5: 1.4MHz, 3MHz, 5MHz, 10MHz LTE Band 7: 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 25: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 26: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz

LTE Band 38: 5MHz, 10MHz, 15MHz, 20MHz LTE Band 41: 5MHz, 10MHz, 15MHz, 20MHz

LTE Band 66: 1.4MHz, 3MHz, 5MHz, 10MHz, 15MHz, 20MHz

TX Frequency : LTE Band 2: 1850 ~ 1910 MHz

LTE Band 4: 1710 ~ 1755 MHz LTE Band 5: 824 ~ 849 MHz LTE Band 7: 2500 ~2570 MHz LTE Band 25: 1850 MHz ~ 1915 MHz

LTE Band 26: 814 MHz ~ 849 MHz LTE Band 38: 2570 MHz ~ 2620 MHz LTE Band 41: 2535MHz ~ 2655MHz LTE Band 66: 1710 MHz ~ 1780 MHz

Modulation type : QPSK, 16QAM

Antenna Type : LDS antenna,

LTE Band 2: Maximum Gain is 0.14dBi.

LTE Band 4: Maximum Gain is 0.44dBi. LTE Band 5: Maximum Gain is -2.52dBi. LTE Band 7: Maximum Gain is 0.13dBi. LTE Band 25: Maximum Gain is 0.14dBi. LTE Band 26: Maximum Gain is -2.52dBi. LTE Band 38: Maximum Gain is 0.13dBi. LTE Band 41: Maximum Gain is 0.13dBi. LTE Band 66: Maximum Gain is 0.44dBi.

Antenna information is provided by applicant.

There is WWAN diversity antenna inside the product, which is only for

receiving function.



Software version : DOOGEE-S120-EEA-Android14.0-20240323

Hardware version : SC6017LU\_MB\_V1.0.1\_20240202

Remark 1: The worst-case simultaneous transmission configuration was evaluated with no non-compliance found. Results in this report are only for 4G function, and there is no other transmitter involved.

2: The LTE Band41 upports frequency is 2535-2655MHz, Due to actual customer needs Using software, the prototype can only operate at 2535-2655 MHZ, other frequencies have been blocked



# 2.2 RELATED SUBMITTAL(S) / GRANT (S)

This submittal(s) (test report) is filing to comply with Section Part 22 subpart H and Part 24 subpart E of the FCC CFR 47 Rules.

# 2.3 TEST FACILITY

Company:	Beijing TIRT Technology Service Co.,Ltd Shenzhen
Address:	104 Building C, Xinmingsheng Industrial Park No.132, Zhangge Old Village East Zone, Zhangge Community, Fucheng Street, Longhua District, Shenzhen, Guangdong, P. R. China
CNAS Registration Number:	CNAS L14158
A2LA Registration Number:	6049.01
FCC Accredited Lab.Designation Number:	CN1366
FCC Test Firm Registration Number:	820690
Telephone:	+86-0755-27087573

# 2.4 ACCESSORIES OF DEVICE (EUT)

Accessories	Adapter	
Manufacturer	/	
Model	TP303C-US	
	Input: AC100-240V~ 50/60Hz 0.7A Max	
Output: USB-C:5.0V=3.0A, 15.0W, 9.0V=3.0A, 27.0W,		
Ratings	12.0V-2.5A,30.0W, 15.0V-2.0A, 30.0W, 20.0V-1.5A,	
	30.0W,	
	PPS:5.0V-11.0V=3.0A 33.0W	
	Power: 33.0W	

# 2.5 TESTED SUPPORTING SYSTEM DETAILS

No.	Description	Manufacturer	Model	Serial Number	Certification or SDoC
1	N/A	N/A	N/A	N/A	N/A

# 2.6 TEST CONDITIONS

Items	Required	Actual
Temperature range:	15-35℃	24℃
Humidity range:	25-75%	56%
Pressure range:	86-106kPa	98kPa



# 2.7 MEASUREMENT UNCERTAINTY

Uncertainty		
Parameter	Uncertainty	
Occupied Channel Bandwidth	±142.12 KHz	
RF power conducted	±0.74 dB	
RF power radiated	±3.25dB	
Spurious emissions, conducted	±1.78dB	
Spurious emissions, radiated (9KHz~30MHz)	±2.56dB	
Spurious emissions, radiated (30MHz~1GHz)	±4.6dB	
Spurious emissions, radiated (Above 1GHz)	±4.9dB	
Conduction Emissions(150kHz~30MHz)	±3.1 dB	
Humidity	±4.6%	
Temperature	±0.7°C	
Time	±1.25%	



# 3 TEST INSTRUMENTS LIST

Name of Equipment	Manufacturer	Model Number	Serial Number	Last Calibration	Due Calibration
EMI Receiver	Rohde&Schwarz	ESIB 40	YH-TIRT-SAC-966 -20220911	2024/01/05	2025/01/04
Integral Antenna	Schwarzbeck	VULB 9163	01314	2022.12.11	2024.12.10
Integral Antenna	Rohde&Schwarz	HF907	RSM2991424	2022.12.11	2024.12.10
Preamplifier	Emtrace	RP01A	'02017	2024/01/05	2025/01/04
Preamplifier	Schwarzbeck	BBV9744	00143	2024/01/05	2025/01/04
Loop Antenna	ZHINAN	ZN30900A	12024	2024/01/05	2025/01/04
Exposure Level Tester	narda	ELT-400	N-0925	2024/01/05	2025/01/04
Horn Antenna	Schwarzbeck	BBHA9170	00956	2024/01/05	2025/01/04
RF Cable	/	LMR400UF-NMNM-7. 0M	/	2024/01/05	2025/01/04
RF Cable	/	SFT2050PUR-NMNM -7.0M	/	2024/01/05	2025/01/04
EMI Receiver	Rohde&Schwarz	ESR7	1316.3003K07-10 2611-mk	2023/11/02	2024/11/01
LISN	Rohde&Schwarz	ENV216	3560.655.12-1029 15-Bp	2023/11/02	2024/11/01
ISN	Schwarzbeck	ENY81	1309.8510.03	2024/01/05	2025/01/04
ISN	Schwarzbeck	ENY81-CAT6	1309.8526.03-101 976-kh	2024/01/05	2025/01/04
RF Cable	\	SFT2050PUR-NMNM -2.0M	\	2024/01/05	2025/01/04
CMW500	ROHDE&SCHWARZ	CMW500	120434	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSU26	200732	2024/01/05	2025/01/04
Spectrum analyzer	ROHDE&SCHWARZ	FSV40-N	101722	2024/01/05	2025/01/04
vector Signal Generator	KEYSIGHT	N5182B	MY56200458	2024/01/05	2025/01/04
vector Signal Generator	HEWLETT PACKARD	83752A	3610A02458	2024/01/05	2025/01/04
Filter	HEWLETT PACKARD	JS0806-F	19K8060209	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8821C	SN6262170409	2024/01/05	2025/01/04
Wireless comprehensive tester	ANRISTU	MT8000A	SN6262166782	2024/01/05	2025/01/04



Report No.:ITEZA202300083RF3

ROB ANT	Hubei world for communication Co.,	SW-700/2700XP-4	/	/	/
	LTD				

# 4 SYSTEM TEST CONFIGURATION

# 4.1 TEST MODE

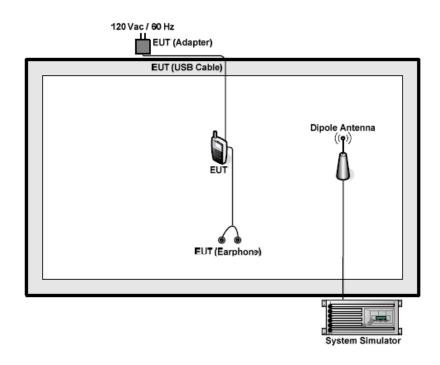
During all testing, EUT is in link mode with base station emulator at maximum power level. The spurious emission measurements were carried out in semi-anechoic chamber with 3-meter test range, and EUT is rotated on three test planes to find out the worst emission.

rotated on three test planes to find out the worst emission.						
	Test modes					
Band	Radiated	Conducted				
LTE Band 2	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 4	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 5	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 7	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 25	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 26	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 38	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 41	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				
LTE Band 66	■ QPSK link, 16QAM link	■ QPSK link, 16QAM link				

Note: Antenna port conducted and radiated test items were performed according to KDB 971168 D01 Power Meas License Digital Systems v03r1 with maximum output power.

Radiated measurements were performed with rotating EUT in different three orthogonal test planes to find the maximum emission.

# 4.2 CONFIGURATION OF TESTED SYSTEM





# 4.3 CONDUCTED OUTPUT POWER

4.3 CONDOCTED OUT					
Test Requirement:	Part 2.1046, Part 22.913(a), Part 24.232(c), Part 27.50(b), Part 27.50(c), Part 27.50(d), Part 27.50(h), Part 90.635				
Test Method:	ANSI C63.26:2015				
Limit:	LTE Band 2: 2W				
	LTE Band 4: 1W				
	LTE Band 5: 7W				
	LTE Band 7: 2W				
	LTE Band 25: 2W				
	LTE Band 26: 100W				
	LTE Band 38: 2W				
	LTE Band 41: 2W				
	LTE Band 66: 1W				
Test setup:	EUT Splitter Communication Tester				
	Power meter  Note: Measurement setup for testing on Antenna connector				
Test Procedure:	The transmitter output port was connected to base station.				
	2. The RF output of EUT was connected to the power meter by RF				
	cable and attenuator, the path loss was compensated to the results				
	for each measurement.				
	3. Set EUT at maximum power through base station.				
	4. Select lowest, middle, and highest channels for each band and				
	different modulation.  5. Measure the maximum burst average power.				
Test Instruments:	Measure the maximum burst average power.  Refer to section 3 for details				
Test mode:	Refer to section 4.1 for details				
Test results:	Pass				
r oot roomo.					

Note: Please refer to Appendix A of the Appendix Test Data.



# 4.4 PEAK-TO-AVERAGE RATIO

4.4 PEAK-TO-AVER	AGE RATIO
Test Requirement:	Part 22.913(d), FCC part24.232(d) and FCC part27.50(d)(5)
Test Method:	ANSI C63.26:2015
Test Limit:	Used complementary cumulative distribution function (CCDF) of analyzer to determine that PAPR will not exceed 13 dB for more than 0.1 percent of the time
Test setup:	SPA  SPA  Communication Tester  SPA  Note: Measurement setup for testing on Antenna connector
Test Procedure:	<ol> <li>The testing follows FCC KDB 971168 D01 v03r01 Section 5.7</li> <li>The EUT was connected to spectrum and system simulator via a power divider</li> <li>Using the CCDF measurement ofspectrum analyzer;</li> <li>Set RBW≥OBW or specified reference bandwidth;</li> <li>Set the number of counts to a value that stabilizes the measured CCDF curve;</li> <li>Set the measurement interval as 1ms</li> <li>Record the maximum PAPR level associated with a probability of 0.1%.</li> </ol>
Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass

Note: Please refer to Appendix B of the Appendix Test Data.



# OCCUPY BANDWIDTH FCC part22.913(a), FCC part24.232(b) and FCC part27.53(a), FCC part Test Requirement: ANSI C63.26:2015 Test Method: Test setup: Communication EUT Splitter SPA Note: Measurement setup for testing on Antenna connector 1.The EUT's output RF connector was connected with a short cable to Test Procedure: the spectrum analyzer, set center frequency to channel center frequency. 2.RBW was set to about 1%-5% of emission OBW, VBW≥ 3 X RBW. 3.Set spectrum analyzer detection mode to peak, and the trace mode to max hold. 4. Use the 99% OBW function, The 99% power OBW can be found on the plot, determine the "-26dB amplitude" as equal to reference value -26dB. Refer to section 3 for details Test Instruments: Refer to section 4.1 for details Test mode: Pass Test results:

Note: Please refer to Appendix C of the Appendix Test Data.



# MODULATION CHARACTERISTIC According to FCC § 2.1047(d), Part 24E & Part 27 there is no specific requirement for digital modulation, therefore modulation characteristic is not presented.



# OUT OF BAND EMISSION AT ANTENNA TERMINALS Part 2.1051 Test Requirement: Part 22.917 Part 24.238 Part 27.53(c)(f) Part 27.53(g) Part 27.53(h) Part 27.53(m) Part 90.691 Test Method: ANSI C63.26:2015 $\leq$ -13dBm(LTE Band5,26(824-849MHz)) Limit: ≤ -13dBm(LTE Band2,25) ≤ -13dBm(LTE Band12, 17, 71) $\leq$ -13dBm(LTE Band4,66) ≤ -25dBm(LTE Band 7, 38, 41) ≤ -13dBm(LTE Band26(814-824MHz)) Test setup: Communication Splitter EUT Tester Filter SPA Note: Measurement setup for testing on Antenna connector Test Procedure: The RF output of the transceiver was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 1MHz, sufficient scans were taken to show the out of band Emissions if any up to 10th harmonic. For the out of band: Set the RBW=1MHz, VBW = 3MHz, Start=30MHz, Stop= 10th harmonic. Band Edge Requirements: In the 1 MHz bands immediately outside and adjacent to the frequency block, a resolution bandwidth of at least 1 percent of the emission bandwidth of the fundamental emission of the transmitter may be employed to measure the out of band Emissions. Refer to section 3 for details Test Instruments: Refer to section 4.1 for details Test mode: **Pass** Test results: Note: Please refer to Appendix D of the Appendix Test Data.



# ERP, EIRP MEASUREMENT Part 2.1046, Part 22.913(a), Part 24.232(b), Part 27.50(b), Part Test Requirement: 27.50(c), Part 27.50(d), Part 27.50(h), Part 90.635 ANSI C63.26:2015 Test Method: ERP≤ 7W(38.45dBm) (LTE Band 5,26(824-849MHz)) Limit: EIRP≤ 2W(33.00dBm) (LTE Band 2,25) ERP≤ 3W(34.77dBm) (LTE Band 13) ERP≤ 3W(34.77dBm) (LTE Band 12,17,71) EIRP≤ 1W(30.00dBm) (LTE Band 4,66) EIRP≤ 2W(33.00dBm) (LTE Band 7,38,41) ERP≤ 100W(50.00dBm) (LTE Band 26(814-824MHz)) Test setup: Below 1GHz Antenna Tower Search EUT RF Test Receiver Turn 1m Ground Plane Above 1GHz EUT Spectrum Amplifier Substituted method: Antenna mast Ground plane d: distance in meters 1-4 meter d:3 meter SPA Substituted Dipole or Horn Antenna Bi-Log Antenna or Horn Antenna



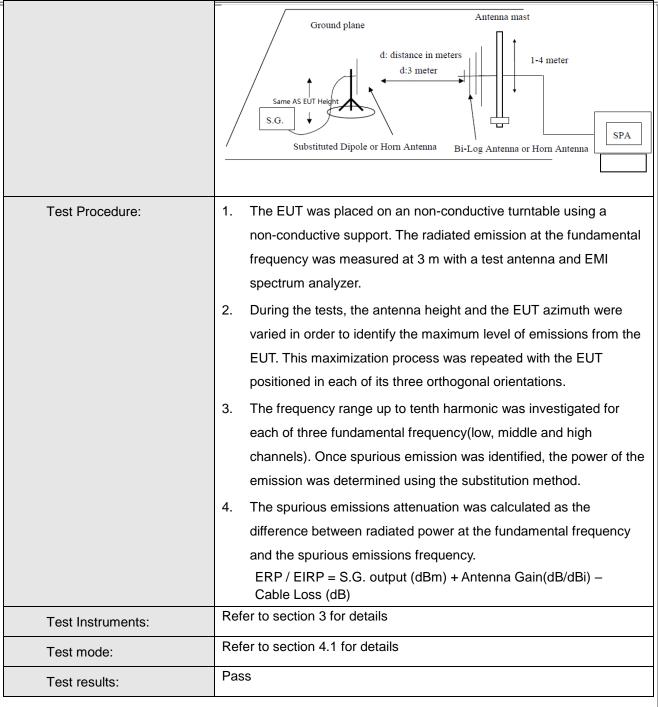
Test Procedure:	The EUT was placed on an non-conductive turntable using a non-conductive support. The radiated emission at the fundamental frequency was measured at 3 m with a test antenna and EMI spectrum analyzer.
	<ol> <li>During the measurement, the EUT was communication with the station. The highest emission was recorded with the rotation of the turntable and the lowering of the test antenna from 4m to 1m. The reading was recorded and the field strength (E in dBuV/m) was calculated.</li> </ol>
	<ol> <li>ERP were measured using a substitution method. The EUT was replaced by dipole antenna connected, the S.G. output was recorded and ERP was calculated asfollows:         ERP = S.G. output (dBm) + Antenna Gain (dBd) – Cable Loss (dB)</li> <li>EIRP were measured using a substitution method. The EUTwas replaced by or horn antenna connected, the S.G. output was recorded and EIRP was calculated asfollows:         EIRP = S.G. output (dBm) + Antenna Gain (dBi) – Cable Loss (dB)</li> </ol>
Test Instruments:	Refer to section 3 for details
Test mode:	Refer to section 4.1 for details
Test results:	Pass
Remark:	H,E1,E2 mean for EUT polarization of X, Y, Z

Note: Please refer to Appendix A of the Appendix Test Data.



# FIELD STRENGTH OF SPURIOUS RADIATION MEASUREMENT Part 2.1053 Test Requirement: Part 22.917 Part 24.238 Part 27.53(c)(f) Part 27.53(g) Part 27.53(h) Part 27.53(m) Part 90.691 Test Method: ANSI C63.26:2015 Limit: ≤ -13dBm(LTE Band 5,26(824-849MHz)) ≤ -13dBm(LTE Band 2,25) ≤ -13dBm(LTE Band 12, 17, 71) ≤ -13dBm(LTE Band 4,66) ≤ -25dBm(LTE Band 7, 38, 41) ≤ -13dBm(LTE Band 26(814-824MHz)) Test setup: Below 1GHz Antenna Tower Search Antenna EUT RF Test Receiver 穒 Turn Ground Plane Above 1GHz Antenna Tower Horn Antenna Spectrum Analyzer Turn Amplifier Substituted method:







# Measurement Data:

### **OPSK Mode**:

QPSK Mode:				
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (IVII 12)	Polarization	Level (dBm)	Lillit (dbill)	Nesuit
3712.31	Vertical	-34.05		
5545.36	V	-37.58		
7475.61	V	-36.85	-13.00	Pass
9247.52	V	-39.61		
11101.42	V			
3705.41	Horizontal	-39.10		
5545.31	Н	-41.52		
7404.74	Н	-42.65	-13.00	Pass
9247.01	Н	-44.54		
11125.41	Н			
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MITIZ)	Polarization	Level (dBm)	Limit (dbin)	Kesuit
3758.61	Vertical	-35.63		
5648.35	V	-37.56		
7535.61	V	-36.25	-13.00	Pass
9412.56	V	-42.64		
11279.31	V			
3758.61	Horizontal	-36.58		
5646.31	Н	-41.85		
7518.62	Н	-43.21	-13.00	Pass
9401.58	Н	-43.25		
11259.25	Н			
Test mode:	LTE Band	2(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (IVII 12)	Polarization	Level (dBm)	Limit (dDin)	Nesuit
3828.31	Vertical	-35.64		
5725.31	V	-37.35		
7638.61	V	-36.58	-13.00	Pass
9551.35	V	-41.05	_	
11452.75	V			
3825.31	Horizontal	-37.35	_	
5731.58	Н	-40.25	_	
7628.65	Н	-42.25	-13.00	Pass
9538.31	Н	-43.01		
11455.52	Н			

- 1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	4(1.4MHz)	Test channel:	Lowest	
- (A411.)	Spurious	Emission	1: :(/15.)	1	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result	
3415.52	Vertical	-35.98			
5128.62	V	-37.02			
6848.35	V	-36.58	-13.00	Pass	
8531.28	V	-42.85			
10235.21	V				
3407.61	Horizontal	-37.52			
5128.21	Н	-42.01			
6839.61	Н	-43.85	-13.00	Pass	
8528.61	Н	-42.08			
10212.36	Н				
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle	
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result	
1 requericy (Wir 12)	Polarization	Level (dBm)	Limit (dbin)	Nesuit	
3445.61	Vertical	-34.25			
5128.12	V	-37.05		Pass	
6928.31	V	-38.53	-13.00		
8648.61	V	-42.12			
10328.52	V				
3446.31	Horizontal	-36.82			
5186.32	Н	-40.21			
6928.22	Н	-43.52	-13.00	Pass	
8648.12	Н	-43.01			
10399.12	Н				
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest	
Frequency (MHz)	•	Emission	Limit (dBm)	Result	
Trequency (Wiriz)	Polarization	Level (dBm)	Limit (dBin)	result	
3503.12	Vertical	-33.72			
5253.27	V	-35.82			
7025.74	V	-35.05	-13.00	Pass	
8765.27	V	-42.74			
10521.55	V				
3507.53	Horizontal	-37.53			
5257.12	Н	-40.74			
7028.61	Н	-42.72	-13.00	Pass	
8769.25	Н	-44.05	]		
10531.57	Н				

- The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	5(1.4MHz)	Test channel:	Lowest
F (MIL)	Spurious	Emission	L''( / ID)	D !!
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1636.54	Vertical	-35.25		
2425.14	V	-38.57		
3224.12	V	-36.38	-13.00	Pass
4153.15	V	-41.28		
4973.21	V			
1786.21	Horizontal	-36.28		
2563.14	Н	-40.17		
3861.25	Н	-42.73	-13.00	Pass
4275.58	Н	-41.27		
5125.31	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (ivii iz)	Polarization	Level (dBm)	Limit (dbin)	Nesuit
1625.31	Vertical	-34.73		
2486.35	V	-36.28		
3276.25	V	-35.79	-13.00	Pass
4286.21	V	-40.25		
5025.15	V			
4756.35	Horizontal	-36.28		
2631.24	Н	-40.21		
3864.25	Н	-42.85	-13.00	Pass
4358.39	Н	-43.25		
5125.31	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Highest
Frequency (MHz)		Emission	Limit (dBm)	Result
1 requeries (IVII 12)	Polarization	Level (dBm)	Limit (dbin)	resuit
1702.21	Vertical	-35.61		
2538.31	V	-36.25		
3438.21	V	-35.78	-13.00	Pass
4382.74	V	-42.12	ļ	
5125.71	V			
1758.31	Horizontal	-37.82		
2863.21	Н	-40.22		
3402.31	Н	-43.28	-13.00	Pass
4358.12	Н	-42.01	]	
5128.85	Н			

- 1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	d 7(5MHz)	Test channel:	Lowest
F (MIL)	Spurious	Emission	L':'( / ID )	D !!
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5214.32	Vertical	-33.28		
4832.52	V	-35.72		
10125.31	V	-35.25	-25.00	Pass
13561.12	V	-41.08		
15125.86	V			
5173.56	Horizontal	-36.58		
7967.25	Н	-41.27		
10135.25	Н	-42.73	-25.00	Pass
12756.32	Н	-43.14		
15135.65	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (Wir 12)	Polarization	Level (dBm)	Limit (abin)	Nesuit
5125.85	Vertical	-34.26		
7613.52	V	-36.02		
10256.13	V	-35.87	-25.00	Pass
13257.13	V	-41.83		
15581.25	V			
5125.88	Horizontal	-38.25		
7753.12	Н	-42.23		
10251.01	Н	-41.85	-25.00	Pass
13807.12	Н	-42.37		
15325.45	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requeries (IVII 12)	Polarization	Level (dBm)	Limit (dbin)	resuit
5254.15	Vertical	-38.21		
7869.61	V	-32.87		
10358.12	V	-35.42	-25.00	Pass
12987.32	V	-42.73		
15325.12	V			
5231.45	Horizontal	-37.52		
7728.12	Н	-41.41		
10358.83	Н	-42.88	-25.00	Pass
12752.10	Н	-43.12	]	
15358.85	Н			

- 1. The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2. Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3. The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	25(5MHz)	Test channel:	Lowest
Fragues av (NALIE)	Spurious	Emission	Line it (dDne)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5125.35	Vertical	-35.25		
7631.25	V	-36.69		
10120.25	V	-37.26	-13.00	Pass
12252.74	V	-38.33		
15281.85	V			
5028.84	Horizontal	-37.12		
7545.58	Н	-38.31		
10525.83	Н	-37.25	-13.00	Pass
12521.21	Н	-40.56		
15254.89	Н			
Test mode:	LTE Band	25(5MHz)	Test channel:	Middle
Fraguency (MHz)	Spurious	Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5256.37	Vertical	-34.26		
7635.12	V	-35.31		
10251.74	V	-35.83	-13.00	Pass
12563.12	V	-40.97		
15358.85	V			
5254.85	Horizontal	-33.12		
7534.87	Н	-38.24		
10250.76	Н	-41.08	-13.00	Pass
13583.84	Н	-42.85		
15321.85	Н			
Test mode:	LTE Band	25(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (Wir 12)	Polarization	Level (dBm)	Limit (dDin)	Nesuit
5251.12	Vertical	-35.21		
7863.21	V	-36.83		
10020.85	V	-34.02	-13.00	Pass
12217.38	V	-40.76		
15365.85	V			
5254.01	Horizontal	-37.82		
7831.55	Н	-40.12		
10384.72	Н	-40.73	-13.00	Pass
12241.12	Н	-42.12		
15398.73	Н			

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- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
Frequency (MHz)	Spi	urious Emission	Limit (dRm)	Result
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result
3485.61	Vertical	-35.62		
7893.73	V	-36.32		
10125.74	V	-33.29	-13.00	Pass
12325.21	V	-40.79		
16251.52	V			
5125.74	Horizontal	-33.21		
7631.73	Н	-41.28		
10251.08	Н	-42.17	-13.00	Pass
12501.49	Н	-40.15		
15258.12	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fragues av. (MIII=)	Spi	urious Emission	Lineit (dDne)	Decult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5128.61	Vertical	-32.12		
7629.65	V	-33.73		
10254.76	V	-35.28	-13.00	Pass
13263.76	V	-40.55		
15521.52	V			
5218.85	Horizontal	-36.51		
7708.72	Н	-40.13		
10256.78	Н	-42.85	-13.00	Pass
12596.31	Н	-40.12		
15250.76	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
[ /MI   _ )	Spi	urious Emission	Lineit (dDne)	Danult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5225.39	Vertical	-34.31		
7813.23	V	-35.58		
10356.28	V	-36.35	-13.00	Pass
12853.72	V	-40.12		
15315.85	V		]	
5125.17	Horizontal	-37.85		
7832.85	Н	-39.61	]	
10315.74	Н	-40.12	-13.00	Pass
12932.28	Н	-42.85		. 400
15252.75	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
Fragues av (MIII-)	Spi	urious Emission	Lineit (dDne)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3928.31	Vertical	-33.21		
7536.12	V	-35.52		
10123.28	V	-33.52	-13.00	Pass
12231.85	V	-41.05		
13284.28	V			
3845.28	Horizontal	-37.36		
7564.21	Н	-39.25		
10123.27	Н	-42.21	-13.00	Pass
12453.15	Н	-43.21		
13277.63	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fraguency (MUz)	Spi	urious Emission	Limit (dDm)	D !!
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3823.74	Vertical	-32.74		
7768.62	V	-35.61	-13.00	Pass
10325.85	V	-33.28		
12986.12	V	-40.12		
15254.74	V			
3854.28	Horizontal	-37.85		
7675.12	Н	-41.29		
10325.85	Η	-40.74	-13.00	Pass
12321.73	Н	-42.12		
15254.28	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
Erogueney (MUz)	Spi	urious Emission	Limit (dRm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3962.51	Vertical	-32.31		
7929.61	V	-31.25		
10325.12	V	-35.69	-13.00	Pass
12254.52	V	-41.28		
15525.49	V			
3847.05	Horizontal	-32.85		
7886.27	Н	-39.61	]	
10325.85	Н	-42.85	-13.00	Pass
12212.28	Н	-43.74		
15528.76	Н			

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- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode	LTE E	Band 38(5MHz)	Test channel:	Lowest
Frequency (MHz)	Spui	rious Emission	Limit (dRm)	Result
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result
2638.21	Vertical	-33.25		Pass
5254.10	V	-35.86		
10583.52	V	-33.28	-25.00	
12213.64	V	-40.01		
13581.01	V			
2636.73	Horizontal	-38.12		
5253.32	Н	-39.82		
10836.28	Н	-42.66	-25.00	Pass
12251.12	Н	-43.76		
13258.47	Н			
Test mode	LTE E	Band 38(5MHz)	Test channel:	Middle
Fraguenov (MUz)	Spui	rious Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2768.02	Vertical	-31.05		Pass
5482.31	V	-37.52		
10658.27	V	-33.77	-25.00	
12863.25	V	-41.99		
15593.15	V			
2681.73	Horizontal	-37.85		
5456.85	Н	-38.61		
10824.32	Н	-42.12	-25.00	Pass
12256.32	Н	-42.74		
15325.12	Н			
Test mode	LTE I	Band 38(5MHz)	Test channel:	Highest
Fragues (MIII-)	Spui	rious Emission	Lineit (alDine)	Dagult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2635.83	Vertical	-32.52		
6892.32	V	-37.15		
10458.31	V	-33.25	-25.00	Pass
12723.12	V	-39.85		
15521.52	V			
2683.33	Horizontal	-33.12		
5212.52	Н	-38.63		
10745.21	Н	-42.12	-25.00	Pass
13254.21	Н	-43.12		
16254.74	Н			

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- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode	LTE E	Band 41(5MHz)	Test channel:	Lowest
Fraguenov (MHz)	Spui	ious Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3685.12	Vertical	-30.46		Pass
8631072	V	-37.25		
10251.32	V	-36.28	-25.00	
12658.62	V	-40.12		
13258.61	V			
3985.32	Horizontal	-36.57		
9831.25	Н	-40.52		
10257.12	Н	-42.42	-25.00	Pass
12264.32	Н	-41.02		
13158.65	Н			
Test mode	LTE E	Band 41(5MHz)	Test channel:	Middle
Frequency (MHz)	Spui	ious Emission	Limit (dBm)	Result
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dbin)	Kesuit
3586.86	Vertical	-33.25		Pass
596324	V	-36.89		
8963.21	V	-35.27	-25.00	
10235.12	V	-40.02		
13685.86	V			
5863.82	Horizontal	-34.58		
7256.12	Н	-42.73		
10325.39	Н	-40.12	-25.00	Pass
12251.73	Н	-33.15		
13256.25	Н			
Test mode	LTE E	Band 41(5MHz)	Test channel:	Highest
(MI I=)	Spui	ious Emission	Lineit (alDine)	Dagult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3125.31	Vertical	-35.61		
5635.12	V	-37.62		
8962.21	V	-36.25	-25.00	Pass
10358.62	V	-40.12		
12759.85	V			
5125.87	Horizontal	-37.52		
8695.76	Н	-40.12	1	
10286.31	Н	-41.05	-25.00	Pass
12657.12	Н	-42.85		
13586.32	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Lowest
Frequency	Spurious	Emission	1: :(/15.)	Result
(MHz)	Polarization	Level (dBm)	Limit (dBm)	
3325.52	Vertical	-33.28		Pass
5686.85	V	-37.38		
7325.29	V	-34.58	-13.00	
8296.31	V	-40.89		
10325.35	V			
3328.75	Horizontal	-37.85		
5251.25	Н	-40.43		
6935.12	Н	-42.73	-13.00	Pass
8863.21	Н	-43.58		
10264.12	Н			
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Middle
Frequency	Spurious	Emission	Limit (dBm)	Result
(MHz)	Polarization	Level (dBm)	Limit (dbin)	Result
2896.31	Vertical	-37.75		
5368.68	V	-38.99		
7536.21	V	-37.53	-13.00	Pass
9863.12	V	-41.25		
10252.25	V			
3015.82	Horizontal	-37.85		
5256.10	Н	-39.85		
7635.85	Н	-42.18	-13.00	Pass
8832.75	Н	-42.32		
10395.11	Н			
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Highest
Frequency	Spurious	Emission	Limit (dDm)	Result
(MHz)	Polarization	Level (dBm)	Limit (dBm)	Kesuit
3758.61	Vertical	-33.86		
5312.25	V	-32.12		
7253.14	V	-35.89	-13.00	Pass
8628.65	V	-43.12		
10458.31	V			
3329.61	Horizontal	-37.85		
5312.74	Н	-42.29	-13.00	
7312.72	Н	-43.05		Pass
8826.31	Н	-43.47		
10122.57	Н			

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- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.

The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst



16 QAM Mode:				
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Lowest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MITIZ)	Polarization	Level (dBm)	Limit (dbin)	Kesuit
3531.41	Vertical	-33.21		Pass
5694.31	V	-35.62		
8631.47	V	-34.85	-13.00	
9698.71	V	-40.52		
11364.20	V			
3625.14	Horizontal	-33.86		
5589.31	Н	-38.61		
7698.78	Н	-42.74	-13.00	Pass
9368.85	Н	-42.12		
12364.21	Н			
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Middle
Fraguesia (MIII-)	Spurious	Emission	Lineit (dDne)	Desuit
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3869.05	Vertical	-33.74		Pass
5831.12	V	-35.85		
7932.78	V	-34.12	-13.00	
9358.31	V	-40.85		
12124.55	V			
3328.61	Horizontal	-37.85		
5578.20	Н	-40.53		
7931.75	Н	-42.87	-13.00	Pass
9893.12	Н	-43.85		
11312.28	Н			
Test mode:	LTE Band	2 (1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (MITIZ)	Polarization	Level (dBm)	Limit (dbin)	Result
2896.84	Vertical	-33.51		
5631.25	V	-38.58		
7861.23	V	-36.85	-13.00	Pass
9276.78	V	-36.12		
12152.85	V			
3763.63	Horizontal	-37.85		
5698.47	Н	-40.28	-13.00	
7531.11	Н	-42.12		Pass
9486.59	Н	-42.17		
11455.80	Н			

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- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	4(1.4MHz)	Test channel:	Lowest
F (MIL)	Spurious	Emission	L''( / ID)	D !!
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3415.21	Vertical	-33.28		
5254.54	V	-36.89		
6324.28	V	-32.12	-13.00	Pass
8683.31	V	-43.58		
11254.25	V			
3325.93	Horizontal	-35.61		
4963.31	Н	-39.61		
7689.28	Н	-42.81	-13.00	Pass
9631.25	Н	-43.87		
10385.74	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (IVII 12)	Polarization	Level (dBm)	Limit (abin)	Nesuit
3289.61	Vertical	-37.82		
5254.85	V	-36.31		Pass
7329.31	V	-35.74	-13.00	
8961.25	V	-40.52		
10256.12	V			
3359.35	Horizontal	-37.74		Pass
5257.72	Н	-38.21		
6869.31	Н	-42.74	-13.00	
9328.58	Н	-41.02		
10425.72	Н			
Test mode:	LTE Band	4(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (ivii iz)	Polarization	Level (dBm)	Limit (abin)	Nesuit
3234.58	Vertical	-35.61		
5125.84	V	-37.59		
8632.12	V	-32.84	-13.00	Pass
9536.75	V	-42.85		
11265.72	V			
3512.89	Horizontal	-36.28		
5368.81	Н	-39.56		
7256.74	Н	-42.81	-13.00	Pass
8936.57	Н	-40.28	1	
10328.74	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	5(1.4MHz)	Test channel:	Lowest
[	Spurious	Emission	Limit (dDas)	Danish
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1963.12	Vertical	-36.85		
2516.31	V	-37.23		
3647.51	V	-38.24	-13.00	Pass
4234.74	V	-40.45		
5639.12	V			
1649.85	Horizontal	-35.98		
2473.85	Н	-40.46		
3299.12	Н	-42.74	-13.00	Pass
4251.88	Н	-43.12		
5048.74	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Middle
Fraguency (MHz)	Spurious	Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
1683.12	Vertical	-35.58		
2512.55	V	-35.12		Pass
3458.56	V	-38.32	-13.00	
4199.25	V	-41.38		
5123.85	V			
1562.12	Horizontal	-38.05		
2312.85	Н	-41.77		
3455.88	Н	-43.12	-13.00	Pass
4183.36	Н	-45.31		
5528.74	Н			
Test mode:	LTE Band	5(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requeries (Wir 12)	Polarization	Level (dBm)	Limit (dDin)	rtesuit
1169.85	Vertical	-37.58		
2359.12	V	-33.12		
3232.87	V	-32.85	-13.00	Pass
4225.92	V	-40.12		
5125.74	V			
1675.25	Horizontal	-33.21		
2543.72	Н	-32.52		
3398.28	Н	-40.84	-13.00	Pass
4243.45	Н	-40.41		
5089.85	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	d 7(5MHz)	Test channel:	Lowest
F (MIL)	Spurious	Emission	L''( / ID)	D !!
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5125.51	Vertical	-33.25		
7328.74	V	-37.01		
9040.76	V	-35.62	-25.00	Pass
12365.74	V	-40.41		
15358.86	V			
5125.99	Horizontal	-33.58		
7328.61	Н	-39.52		
9631.25	Н	-42.12	-25.00	Pass
12456.51	Н	-43.85		
15268.76	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (Wir 12)	Polarization	Level (dBm)	Limit (dDin)	Nesuit
5125.31	Vertical	-33.25		
7689.52	V	-35.96		Pass
10128.01	V	-39.85	-25.00	
12659.77	V	-42.44		
15228.43	V			
5128.62	Horizontal	-39.21		
7627.24	Н	-42.84		
10259.23	Н	-41.74	-25.00	Pass
12315.74	Н	-43.28		
15328.85	Н			
Test mode:	LTE Band	d 7(5MHz)	Test channel:	Highest
Frequency (MHz)	•	Emission	Limit (dBm)	Result
1 requeries (ivii iz)	Polarization	Level (dBm)	Limit (dBin)	result
5028.31	Vertical	-35.35		
7838.85	V	-37.15		
10315.14	V	-33.56	-25.00	Pass
12963.28	V	-41.01		
15631.74	V			
5129.61	Horizontal	-33.58		
7832.86	Н	-40.74		
10201.25	Н	-44.95	-25.00	Pass
12863.48	Н	-45.32		
15501.52	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band	25(5MHz)	Test channel:	Lowest
Fragueray (MIII-)	Spurious	Emission	Line it (dDne)	Dogult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5128.31	Vertical	-32.81		Pass
7359.74	V	-37.52		
10128.85	V	-35.84	-13.00	
12239.74	V	-40.25		
13501.28	V			
5135.79	Horizontal	-37.85		
7529.02	Н	-40.75		
10125.74	Н	-42.85	-13.00	Pass
12021.05	Н	-42.12		
13528.31	Н			
Test mode:	LTE Band	25(5MHz)	Test channel:	Middle
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
Frequency (IVIF12)	Polarization	Level (dBm)	Limit (dbin)	Kesuit
5025.85	Vertical	-33.25		Pass
7283.51	V	-32.85		
10028.85	V	-35.61	-13.00	
12691.74	V	-40.74		
15453.25	V			
5048.85	Horizontal	-36.74		
7631.25	Н	-42.74		
10251.76	Н	-40.23	-13.00	Pass
12021.58	Н	-43.74		
15458.25	Н			
Test mode:	LTE Band	25(5MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requeries (IVII 12)	Polarization	Level (dBm)	Limit (dbin)	rtesuit
5203.21	Vertical	-32.12		
7728.12	V	-33.85		
10252.21	V	-37.85	-13.00	Pass
12712.01	V	-40.12		
15452.74	V			
5212.85	Horizontal	-36.84		
7780.85	Н	-39.65		
10273.39	Н	-42.74	-13.00	Pass
12715.25	Н	-43.12		
15523.64	Н			

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- 5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
Fraguency (MHz)	Sp	urious Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3245.62	Vertical	-33.51		
7245.61	V	-32.74		Pass
10125.45	V	-31.28	-13.00	
12452.74	V	-42.74		
15128.37	V			
3658.47	Horizontal	-36.84		
7528.31	Н	-40.14		
10089.33	Н	-42.74	-13.00	Pass
12486.58	Н	-43.14		
15128.28	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fragues av (MILIT)	Sp	urious Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
5027.21	Vertical	-32.12		
7629.30	V	-33.86		Pass
10325.75	V	-35.61	-13.00	
12687.79	V	-41.28		
15318.28	V			
5125.76	Horizontal	-36.89		Pass
7214.05	Н	-40.84		
10254.78	Н	-42.75	-13.00	
12725.89	Н	-43.85		
15325.25	Н			
Test mode(814-824MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
Fragues av (MILIT)	Sp	urious Emission	Limit (dDm)	Dogult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
5212.78	Vertical	-33.28		
7729.21	V	-35.54		Pass
10314.52	V	-35.05	-13.00	
12854.02	V	-42.74		
15536.46	V			
5301.58	Horizontal	-36.85	-13.00	
7829.41	Н	-40.74		
10158.43	Н	-42.47		Pass
12836.48	Н	-44.05		
15329.79	Н			

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- 5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 6 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Lowest
Eroguopov (MHz)	Sp	urious Emission	Limit (dRm) Popult	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3912.51	Vertical	-35.68		
7636.58	V	-37.81		Pass
10045.61	V	-36.89	-13.00	
12586.52	V	-40.74		
13596.33	V			
3936.84	Horizontal	-37.85		
7661.85	Н	-43.14		
10125.74	Н	-42.74	-13.00	Pass
12312.74	Н	-43.74		
13287.12	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Middle
Fraguency (MHz)	Sp	urious Emission	Limit (dDm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	
3812.58	Vertical	-35.84		
7636.74	V	-33.12		Pass
10325.74	V	-32.74	-13.00	
12475.67	V	-40.74		
15385.73	V			
3812.74	Horizontal	-38.85		Pass
7610.58	Н	-39.85		
10358.74	Н	-42.54	-13.00	
12728.45	Н	-40.74		
15358.56	Н			
Test mode(824-849MHz):	LTE	Band 26(5MHz)	Test channel:	Highest
Fraguency (MHz)	Sp	urious Emission	Limit (dDm)	Docult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3758.61	Vertical	-36.74		Pass
7836.85	V	-35.74		
10315.74	V	-37.01	-13.00	
12470.16	V	-40.74		
15525.08	V			
3827.25	Horizontal	-37.85	-13.00 Pass	
7810.74	Н	-39.85		
10231.41	Н	-42.74		Pass
12505.27	Н	-41.05		
15254.43	Н			

- 4 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 6 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode	LTE	Band 38(5MHz)	Test channel:	Lowest
Fraguency (MHz)	Spi	urious Emission	Limit (dRm) Rosu	
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
2364.36	Vertical	-34.02		
5276.41	V	-38.74		Pass
10248.61	V	-38.74	-25.00	
12893.5	V	-41.85		
13483.45	V			
3102.58	Horizontal	-37.85		Pass
5276.94	Н	-42.15		
10027.71	Н	-40.85	-25.00	
12758.31	Н	-45.86		
13027.58	Н			
Test mode	LTE	Band 38(5MHz)	Test channel:	Middle
Frequency (MHz)	Spi	urious Emission	Limit (dRm)	Pocult
Frequency (MHZ)	Polarization	Level (dBm)	Limit (dBm)	Result
2586.37	Vertical	-34.85		
5274.41	V	-37.25		Pass
10574.12	V	-35.96	-25.00	
12757.85	V	-41.02		
15631.89	V			
2568.30	Horizontal	-33.74		Pass
5247.35	Н	-40.75		
10861.52	Н	-42.38	-25.00	
12369.42	Н	-46.12		
15457.01	Н			
Test mode	LTE Band 38(5MHz)		Test channel:	Highest
Frequency (MHz)	Spi	urious Emission	Limit (dBm)	Result
r requericy (wiriz)	Polarization	Level (dBm)	Limit (ubin)	Nesult
2578.74	Vertical	-35.91		Pass
5758.65	V	-38.02		
10657.04	V	-37.85	-25.00	
12682.14	V	-42.85		
16278.54	V			
2629.86	Horizontal	-38.73	-25.00	
5501.64	Н	-42.12		
10275.74	Н	-43.74		Pass
12997.74	Н	-43.02		
16381.28	Н		7	

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- The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode	LTE	Band 41(5MHz)	Test channel:	Lowest
Fraguenov (MHz)	Spurious Emission		Limit (dDm)	Dooult
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
4836.12	Vertical	-36.32		
9931.05	V	-35.76		Pass
10254.13	V	-34.25	-25.00	
12287.36	V	-41.74		
13028.45	V			
4908.38	Horizontal	-35.84		
9910.75	Н	-43.73		
10100.35	Н	-40.72	-25.00	Pass
12569.02	Н	-42.74		
13218.25	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Middle
Frequency (MHz)	Spu	urious Emission	Limit (dBm)	Result
Frequency (MH2)	Polarization	Level (dBm)	Limit (ubin)	
5074.05	Vertical	-35.83		Pass
10010.35	V	-37.02		
12218.43	V	-36.82	-25.00	
13457.86	V	-40.11		
15318.30	V			
5038.67	Horizontal	-36.93		Pass
10124.05	Н	-40.01		
12458.35	Н	-42.85	-25.00	
13254.02	Н	-41.74		
15471.20	Н			
Test mode	LTE	Band 41(5MHz)	Test channel:	Highest
Frequency (MHz)	Spu	urious Emission	Limit (dBm)	Result
r requericy (ivii iz)	Polarization	Level (dBm)	Limit (abin)	Nesuit
5125.38	Vertical	-36.02		
10147.37	V	-37.52		Pass
12123.02	V	-33.01	-25.00	
13241.36	V	-40.74		
15258.38	V			
5014.33	Horizontal	-36.98		Pass
10325.78	Н	-41.27	-25.00	
12751.41	Н	-42.35		
13593.63	Н	-43.05		
13393.03				

- 4 The emission behaviour belongs to narrowband spurious emission,all modes investigated and only worst case is reported.
- 5 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 6 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Lowest
- 441)	Spurious Emission			<b>5</b>
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3413.21	Vertical	-33.85		
5236.24	V	-37.52		Pass
6705.61	V	-33.72	-13.00	
8328.47	V	-41.01		
10221.74	V			
3412.79	Horizontal	-36.89		
5205.74	Н	-39.56		
6857.85	Н	-41.85	-13.00	Pass
8536.17	Н	-43.85		
10273.25	Н			
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Middle
Eroguenov (MHz)	Spurious	Emission	Limit (dPm)	Result
Frequency (MHz)	Polarization	Level (dBm)	Limit (dBm)	Result
3433.64	Vertical	-36.05		Pass
5125.18	V	-35.85		
6938.83	V	-37.12	-13.00	
8721.52	V	-40.05		
10351.01	V			
3328.30	Horizontal	-35.74		Pass
5254.96	Н	-40.79		
6939.21	Н	-42.01	-13.00	
8702.88	Н	-42.74		
10583.13	Н			
Test mode:	LTE Band 6	66(1.4MHz)	Test channel:	Highest
Frequency (MHz)	Spurious	Emission	Limit (dBm)	Result
1 requericy (Wir 12)	Polarization	Level (dBm)	Limit (dbin)	Nesuit
3328.61	Vertical	-32.74		
5123.74	V	-31.08		Pass
7039.27	V	-33.05	-13.00	
8702.28	V	-41.85		
10533.89	V			
3533.12	Horizontal	-36.85		
5271.86	Н	-37.02	-13.00 Pass	
7031.02	Н	-42.12		Pass
8793.28	Н	-43.85		
10528.05	Н			

- 1 The emission behaviour belongs to narrowband spurious emission, all modes investigated and only worst case is reported.
- 2 Remark"---" means that the emission level is too low (20dB lower than the limit) to be measured
- 3 The emission levels of below 1 GHz are very lower (20dB lower than the limit) than the limit and not show in test report.



Test Requirement:	Part 2.1055(a)(1)(b), Part 22.355  Part 24.235 , Part 27.54, Part 90.213	
Test Method:	ANSI C63.26:2015	
Limit:	2.5ppm(Part 22)	
	Within the authorized bands of operation(Part 24, Part 27)	
Test setup:	Temperature Chamber	
	Spectrum analyzer EUT  Att.	
	Variable Power Supply  Note: Measurement setup for testing on Antenna connector	
Test procedure:	<ol> <li>The equipment under test was connected to an external DC por supply and input rated voltage.</li> <li>RF output was connected to a frequency counter or spectra analyzer via feed through attenuators.</li> <li>The EUT was placed inside the temperature chamber.</li> <li>Set the spectrum analyzer RBW low enough to obtain the desi frequency resolution and measure EUT 25°C operating frequency as reference frequency.</li> <li>Turn EUT off and set the chamber temperature to –20°C. After temperature stabilized for approximately 30 minutes recorded frequency.</li> <li>Repeat step measure with 10°C increased per stage until highest temperature of +50°C reached.</li> </ol>	
Test Instruments:	Refer to section 3 for details	
Test mode:	Refer to section 4.1 for details	
Test results:	Pass	
Remark:	If all frequencies stability are comply with the lower limit, then all result can be considered qualified	



# 4.11 FREQUENCY STABILITY V.S. VOLTAGE MEASUREMENT Part 2.1055(d)(1)(2) Test Requirement: Part 22.355 Part 24.235 Part 27.54 Part 90.213 Test Method: ANSI C63.26:2015 2.5ppm Limit: Band II & Band VII should be within authorized band. Test setup: Temperature Chamber EUT Spectrum analyzer Att. Variable Power Supply Note: Measurement setup for testing on Antenna connector Set chamber temperature to 20°C. Use a variable DC power source Test procedure: to power the EUT and set the voltage to rated voltage. Set the spectrum analyzer RBW low enough to obtain the desired frequency resolution and recorded the frequency. Reduce the input voltage to specified extreme voltage variation (+/-15%) and endpoint, record the maximum frequency change. Refer to section 3 for details Test Instruments: Refer to section 4.1 for details Test mode: **Pass** Test results: 1. Manufacturer specified the battery operating end point voltage is Remark: 3.61VDC, max voltage is 4.18VDC. 2. If all frequencies stability are comply with the lower limit, then all

Note: Please refer to Appendix Fof the Appendix Test Data.

results can be considered qualified



## 4.12 TEST SETUP PHOTO







## 4.13 PHOTOS OF EUT





















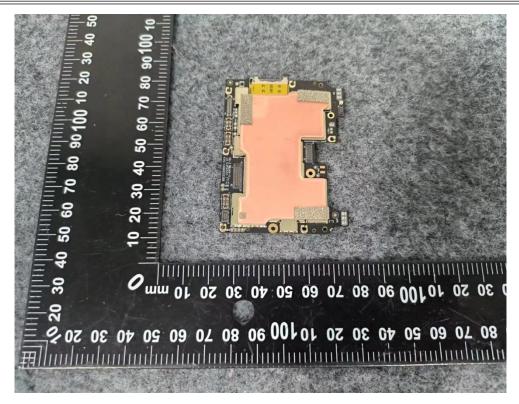


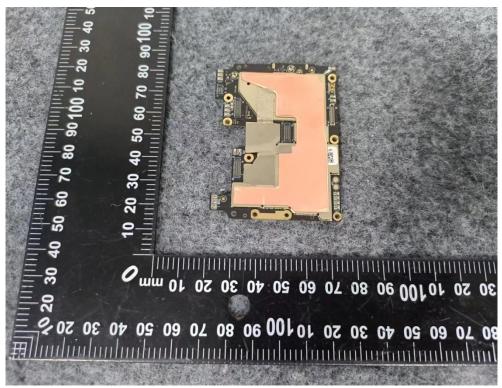




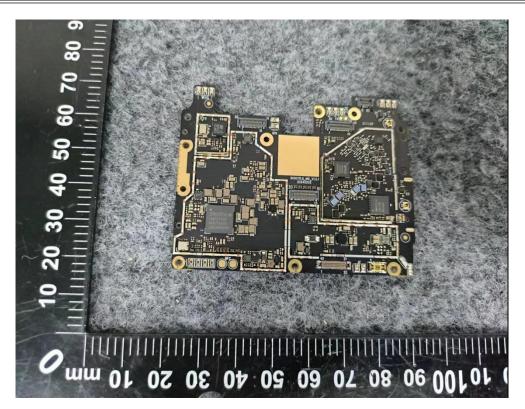


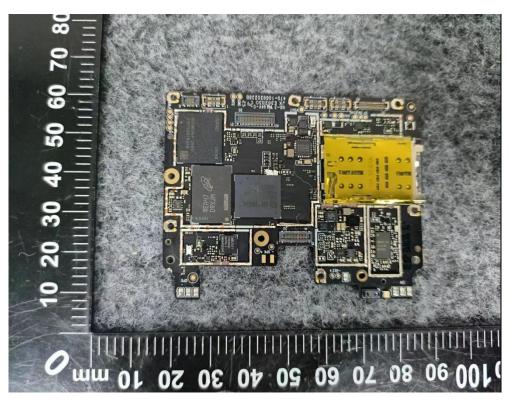




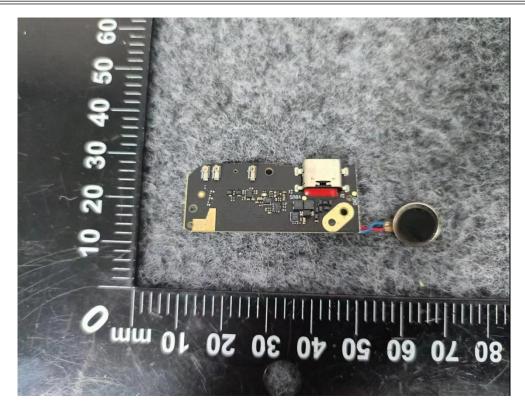


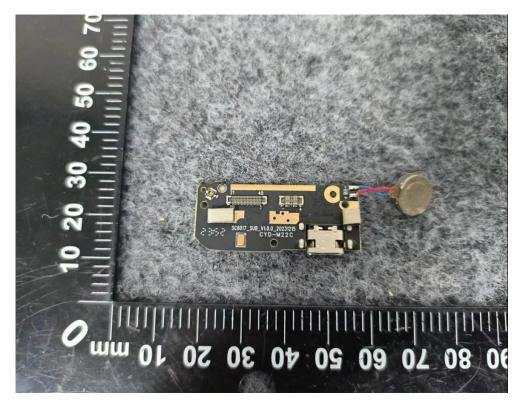
















-----END OF REPORT-----